

Search Notes**Application/Control No.**

09/775,680

Examiner

Cheukfan Lee

Applicant(s)/Patent under Reexamination

MATSUDA, SHINYA

Art Unit

2627

SEARCHED

Class	Subclass	Date	Examiner
358	909.1	12/28/2005	C.L.
	450		
	497,474		
	494		
	527,505		
348	218.1		
	219.1		
	36		
	39		
	37		
382	312		
	248		
	318		
	319		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST search: terms include: camera eith (large\$2 adj2 format adj2 (image document original manuscript))		
search terms (cont.): (overhead (over adj head)) adj3 (camera, (partial adj2 (areas regions images), sequence		
Inventor search		